

Application/Control No.	Applicant(s)/Patent under Reexamination
10/025,960	TANAKA, YOICHIRO
Examiner	Art Unit
Brian E. Miller	2652

SEARCHED								
Class	Subclass	Date	Examiner					
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INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				

(INCLUDING SEARCH STRATEGY)					
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